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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Yoshinori Hino et al.                      Art Unit : 2826  
Serial No. : 10/076,154                                      Examiner : Tan N. Tran  
Filed : February 14, 2002  
Title : SEMICONDUCTOR DEVICE AND MANUFACTURING METHOD THEREOF

Commissioner for Patents  
Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

Copies of the references listed on the attached form PTO-1449 are enclosed.

This statement is being filed after a first Office action on the merits, but before receipt of a final Office action or a Notice of Allowance. A check for \$180 in payment of the late submission fee of §1.17(p) is enclosed. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Chris T. Mizumoto  
Reg. No. 42,899

Date: April 23, 2003

Fish & Richardson P.C.  
45 Rockefeller Plaza, Suite 2800  
New York, New York 10111  
Telephone: (212) 765-5070  
Facsimile: (212) 258-2291

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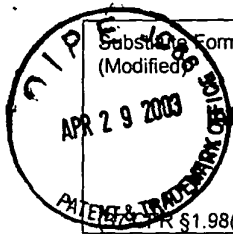
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Substitute Form PTO-1449  
(Modified)U.S. Department of Commerce  
Patent and Trademark OfficeAttorney's Docket No.  
10417-118001Application No.  
10/076,154

### Information Disclosure Statement by Applicant

(Use several sheets if necessary)

Applicant  
Yoshinori Hino et al.Filing Date  
February 14, 2002Group Art Unit  
2826

### U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

### Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

### Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	Taiwanese Office Action dated November 1, 2002
	AR	Clement H. Wann, "A Comparative Study of Advanced MOSFET Concepts", <u>IEEE Transactions of Electric</u> , Volume 43, (1996)
	AS	"Phenomena in Graded Junction Devices"; <u>Texas Instruments Incorporated</u>
	AT	McGraw-Hill, "ULSI Technology", (1996)

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.